

**1997 21st INTERNATIONAL CONFERENCE
ON MICROELECTRONICS**

PROCEEDINGS



Niš, Yugoslavia
14-17 September 1997

Volume 1

organized by
Yugoslavia IEEE Section - Electron Devices Chapter

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IEEE Electron Devices Society



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CONTENTS

VOLUME 1

Plenary Sessions

Invited Keynote Paper

Yugoslavia in Global Microelectronics World

Malcolm Penn 3

Invited Keynote Paper

Silicon MOSFET Scaling Beyond 0.1 Micron

H. Iwai 11

Invited Keynote Paper

Sub-Quarter Micron Silicon Integrated Circuits and Single Wafer Processing

R. Singh 19

Invited Keynote Paper

Decreasing the Time-to-Market Through Virtual Risk Assessment and Risk Mitigation

M. Pecht, P. McCluskey, N. West, S. Azarm, J. Pecht 25

Invited Keynote Paper

New Development in Four-Terminal Device Concept

T. Shibata, T. Ohmi 31

Workshop Technology CAD

A Parallel Tool for the Simulation of Thermal Oxidation and Diffusion Processes

M. Hackenberg, W. Joppich, T. Sontowski, S. Mijalković 35

A Comprehensive System for Submicron-Device Simulation

M. Rudan, M. Lorenzini, M. C. Vecchi, S. Reggiani 41

What Could a Virtual Wafer Look Like?

T. Halama 49

Workshop Microsystem Technologies

From Simple Devices to Promising Microsystems Applications

Ph. Lerch, O. Dubochet, Ph. Renaud 59

Microfabricated Biosensors and Microsystems

P. Hesketh, S. Živanović, Y. Ming, S. Pak, S. Svojanovsky, J. Cunneen, S. Caraffini, J. Boyd, J. Stetter,
S. Lunte, G. Wilson 63

Market-Oriented Development and Production of Microdevices

W. Ehrfeld, V. Hessel, K.-P. Kamper, M. Lacher, A. Picard, M. Schmidt, Ch. Schulz 71

Session Semiconductor Physics and Characterization

Linear Model Application for the Design of Transparent Conductive In₂O₃ Coatings G. Golan, A. Axelevitch, E. Rabinovitch	83
Design of BaTiO₃-Ceramics Reactive Properties - Symbolic Approach V. Mitić, P. Petković, M. Radmanović	87
Photoluminescence Spectra of High Temperature Vacuum Annealed Porous Silicon D. B. Dimitrov, D. Papadimitriou, G. Beshkov	91
Dispersion of Refractive Index in Degenerate Mercury Cadmium Telluride Z. Jakšić, O. Jakšić	95
One Dimensional Si-SiO₂ Photonic Crystal with Defects Intended for Use in Infrared Spectral Region Z. Djurić, R. Petrović, D. Randjelović, T. Danković, Z. Jakšić, W. Ehrfeld, G. Feiertag, H. Freimuth	99
Thermal Emission Current from the Channel Surface in Micro Channel Plate V. Apanasovich, E. Chudovskaja	103
Electronic Deformation Mechanism in Frequency Transmission Photoacoustic Effect in Semiconductors D. Todorović, P. Nikolić, A. Bojčić, K. Radulović	107
Characterization of the Silicon Nitride-Thermal Oxide Interface in ONO Structures by ELS, XPS, Ellipsometry, and Numerical Simulation V. Gritsenko, Yu. Morokov, Yu. Novikov, I. Petrenko, S. Svitashova, H. Wong, R. Kwok, R. Chan	111
A Study of the Electrical Properties of Ion Implanted MnNiCuFeO Ceramics B. Li, J. A. S. Dias	115

Poster Session Semiconductor Physics and Characterization

Electron States of Ultrathin Crystals D. Mirjanić, J. Šetrajčić, S. Stojković, I. Vragović, S. Jaćimovski	21
Spatial Distribution of Free-Carriers in GaAs Films S. Lazarev, S. Markoski, D. Mirjanić, M. Pantić, J. Šetrajčić	25
Bloch Oscillations in Superlattice Simulated by the Monte Carlo Method J. Voves, H. Čermakova	129
Synthesis and Characterization of CdS/SiO₂ Particles with Quantum Dot Quantum Well Structure M. Čomor, Z. Šaponjić, N. Dimitrijević, J. Nedeljković	133
Room-Temperature Quantum-Constriction Rectifier R. Šordjan, K. Nikolić	137
Optimization of Intersubband Resonant Second-Order Susceptibility Using the Supersymmetric Quantum Mechanics S. Tomić, V. Milanović, Z. Ikonić	141
The Influence of the Self-Consistency on Intraband Optical Transitions in Semiconductor Quantum Dot G. Todorović, V. Milanović, Z. Ikonić, D. Indjin	145
The Electronic Structure of Bragg-Confined Semiconductor Structures in Perpendicular Magnetic Field N. Milošević, D. Indjin, V. Milanović, Z. Ikonić	149

The Influence of Permanent Dipole Moments on Second Harmonic Generation in Asymmetric Semiconductor Quantum Wells S. Kočinac, Z. Ikonić, V. Milanović	153
On Equispaced Levels Hamiltonians with the Variable Effective Mass Following the Potential V. Milanović, Z. Ikonić, D. Tjapkin	157
Radiation Caused by Direct and Indirect Transitions in Silicon at Avalanche and Secondary Breakdown T. Puritis, J. Kaupužs	161
Visible Hot Electron Electroluminescence from Si in Tunnel MIS Junction I. Grekhov, A. Shulekin, M. Vexler	165
Degradation Mechanism of InP MOS Structures on the Basis of Al₂O₃ G. Korotchenkov	169
A Proposed Velocity-Electric Field Relationship for Modeling Compound Semiconductor Devices P. Chakrabarti, M. Madheswaran	173
Einstein Relation and Transport Equations in Heavily Doped Silicon A. Trajković, S. Ristić, Z. Prijić, S. Mijalković	177
Investigation of Transport Properties of Carriers in GaAs Using The PA Method A. Bojičić, D. Todorović, P. Nikolić, V. Blagojević, K. Radulović	181
Determination of Transport Parameters in Heavily Doped n-type InP M. Živanov, Lj. Živanov	185
A Modified Model for Resistivity of Thin Polysilicon Films in the Linear Region on I-V Characteristics D. Mitić, D. Petković	189
An Approximate Evaluation of the Threshold Voltage of the Metal-Oxide-Polysilicon Structure D. Petković	193
Structural and Compositional Surface Inhomogeneities of Laser Annealed Hg_{1-x}Cd_xTe Estimated by Raman Spectroscopy M. Šćepanović, M. Jevtić	197
Some Characteristics of Amorphous Semiconductors of the As-S-Se-Te-I Systems S. Lukić, V. Khiminets, D. Petrović, M. Garić, M. Avramov	201
Optical Properties of TiN Thin Films for Microelectronics Applications M. Zlatanović, D. Šešum, Dj. Djukić	205
Homogeneous Electric Field Generation Using Biconical Electrodes D. Veličković, Z. Cvetković	209

Session Device Physics and Modeling

Invited Keynote Paper

Noise Properties of Microwave Heterojunction Bipolar Transistors R. Plana, L. Escotte	215
---	-----

Invited Keynote Paper

AlGaAs/GaAs Heterojunction Bipolar Transistor Reliability: Device Modeling and SPICE Simulation J. Liou, S. Shew, C. Huang	223
--	-----

Invited Keynote Paper

Performances of Low-Voltage, Low Power SOI CMOS Technology J.-P. Colinge	229
Correlation Between Hot-Electron Light Emission and Currents in Pseudomorphic HEMTs P. Cova, F. Fantini, M. Manfredi	237
Influence of Thermal Phenomena on the R. F. Behaviour of Power Heterojunction Bipolar Transistors and Optimization P. Souverain, A. Cazarre, T. Camps, M. Faleh, J. Tasselli, A. Marty, J.P. Bailbe.	241
Efficient MESFET Noise Modeling Including Correlation Coefficient V. Marković, B. Milovanović, N. Maleš-Ilić	245
Microwave Radiation Control of Semiconductor Structures with Tunnel-Thin P-N Transitions D. Usanov, A. Skripal	249
Comparison of the Main Models of Generation-Recombination Space-Charge Current in Abrupt PN Junction A. Gaci, A. Maxim, M. Ahmadpanah, D. Andreu, J. Boucher.	253
Small-Signal Analysis of Short Base Transport by Transmission Line Model J. Karamarković, N. Janković	257
Non-quasi Static Modeling of Bipolar Transistor for CAD Applications N. Rinaldi	261
Interference Effects Influence on Short Circuit Current of Resonant-Cavity Enhanced Photodetectors Z. Djurić, T. Danković, D. Randjelović, Z. Šušnjar	265
Automatic Parameter Extraction Technique for PiN Diode Circuit Model A. Strollo, E. Napoli, L. Fratelli, G. Giannini.	269
Investigation of MOSFET Operation in Bipolar Mode V. Pershenkov, V. Belyakov, S. Cherepko, I. Shvetzov-Shilovsky, V. Abramov	273
Current Instabilities in the Auger Transistor E. Ostroumova, A. Rogachev	277
On the Extraction of the Effective Channel Length of MOSFETs Z. Latif, A. Ortiz-Conde, J. Liou, F. Garcia Sanchez	281
On the Extraction of the Threshold Voltage of MOSFETs A. Ortiz-Conde, E. Gouveia Fernandes, J. Liou, Md. Rofiqul Hassan, F. Garcia Sanchez, G. De Mercato, W. Wong, O. Montilla Castillo	85
Method for Series Resistance Extraction Using the Saturation Region of MOSFETs A. Popescu, A. Rusu, D. Steriu, A. Chovet, A. Ionescu.	289
Switching Characteristics and Static Parameter Extraction in PD SOI MOSFET's L. Perron, C. Hamaguchi, A. Lacaita, S. Maegawa, Y. Yamaguchi	293
Design of SOI Memory Cell Z. Stanojević, D. Ioannou, B. Loncar, P. Osmokrović	297

Poster Session Device Physics and Modeling

High Barrier Ag, Al, Au, Pt/InGaAs Schottky Diodes H. T. Wang, L. B. Chang, S. T. Chou, Y. C. Cheng	303
Photosensitivity Control of Detectors Based on Surface Plasmon-Polariton Resonance in Schottky Structure N. Dmitruk, O. Mayeva, S. Mamikin, P. Romanenko, O. Yastrubchak	309
Photoresponse of InGaAsP-based p-doped Quantum Well Infrared Photodetectors M. Tadić, C. Jelen, S. Slivken, M. Razeghi	315
In-Plane Electron Dynamics and Hot Electron Effects in a Quantum Cascade Laser M. Tadić, S. Slivken, C. Jelen, M. Razeghi	319
Extremely Radiation Stable Rectifiers and Photovoltaic Converters Based at Thin-Film Heterojunctions of Intrinsic Semiconductors I. Volovichev, Yu. Gurevich, V. Koshkin	323
Pulse Response of a Resonant Cavity Enhanced Metal-Semiconductor-Metal Photodetector P. Nikolić, D. Gvozdić, J. Radunović	327
Analysis of the Linear and Nonlinear Time Response of a P-i-N Photodiode by Two-Valley Model P. Matavulj, D. Gvozdić, J. Radunović	331
Properties of a T-Shaped Quantum Interference 'Transistor' as an Electronic Device K. Nikolić, R. Šordjan	335
Optimization of Base Doping Profile for Minimum Transit Time in Bipolar Transistors P. Rinaldi, N. Rinaldi	339
Modeling of the Threshold Voltage of Long and Short-Channel Fully Depleted SOI MOSFETs with Back Gate Substrate Induced Surface Effects M. Imam, M. Osman, A. Osman	343
Analytical Modeling of the Device Conductances of Lightly Doped Drain (LDD) MOSFETs C. Thomas, M. Khanna, S. Haldar, R. Gupta	347
An Analytical Continuous Model of a Fully Depleted SOI MOSFET Applicable for CAD M. Jurczak, A. Jakubowski	351
Modeling of Radiation-Induced Mobility Degradation in MOSFETs N. Stojadinović, S. Golubović, V. Davidović, S. Djorić-Veljković, S. Dimitrijević	355
Investigation of Radiation Sensitivity and Post-Irradiation Thermal Sensitivity of MOS Transistor M. Odalović, Z. Pavlović, B. Vučković, I. Manić	357
Influence of the Temperature on the Equivalent Noise Resistance of HEMT's at Microwave Frequencies F. DiPrima, A. Caddemi, M. Sannino	361
Quantum Approach to GaAs MESFETs R. Šašić, R. Ramović, D. Tjapkin	365

Session Power Technologies and Devices

Invited Keynote Paper

Avalanche Characteristics of MOS Transistors

P. Rossel, H. Tranduc, D. Montcoqut, G. Charitat, I. Pages 371

Invited Keynote Paper

Thermal Effects and Electro-Thermal Modeling in Power Bipolar Transistors

G. Breglio, S. Pica, P. Spirito 383

Deep Energy Levels in Power Diodes Introduced by Iridium Diffusion

V. Benda, M. Černík, D. Štepková 391

The On-Resistance Limits of High Cell Density Power MOSFET's

F. Morancho, H. Tranduc, P. Rossel 395

A 3D, Physically Based Compact Model for IC VDMOS Transistors

J. Victory, C. McAndrew, R. Thoma 399

Temperature Distribution in VDMOS Power Transistor Cells

Z. Pavlović, I. Manić, Z. Prijić 403

Session Hybrid Technologies and Devices

High Pressure Effect on Polymer Thick-Film Resistors

A. Dziedzic, A. Magiera, R. Wisniewski 409

Low-Frequency Noise in Thick-Film Structures Caused by Traps in Glass Barriers

I. Mrak, M. Jevtić, Z. Stanimirović 413

Modeling and Optimization of Multilayer Thick Film Inductors

S. Jenei, O. Aleksić, Lj. Živanov 417

Some Criteria of Topology Selection for Hybrid Converters

S. Radošević, M. Lazić, R. Ramović 421

Poster Session Hybrid Technologies and Devices

Polymer Thick-Film Resistors-Chosen Physicochemical and Electrical Properties

A. Dziedzic 427

Analysis of Thick Film Thermistor Geometries

O. Aleksić, P. Nikolić, V. Jokić, V. Pejović, J. Pavlović, S. Djurić 431

Universal DSP Module Implemented by SMT-Area Array Packaging Technology

D. Jovanović, M. Lutovac, R. Djenić 435

VOLUME 2

Session Process and Device Simulation

Invited Keynote Paper

Technology CAD: Process and Device Simulation

H. Kosina, S. Selberherr 441

Invited Keynote Paper

Mixed Mode Simulation for Power System Optimization

M. Trivedi, K. Shenai 451

Artificial Neural Networks for Reverse Engineering Bipolar Transistors

R. Ferguson, D. Roulston 459

Extraction of Power VDMOS Transistor Model Parameters Using Neural Networks

T. Trajković, P. Igić, N. Stojadinović 463

Simulation of Electrical Burnout of MOSFET Structures

V. Vashchenko, J. Martynov, V. Sinkevitch 467

Characterization, Simulation and Macro-Modelling of Vertical Hall Devices

Z. Randjelović, R. Popović 471

Hierarchical Modelling of Microsystems in an Object-Oriented HDL

Ž. Mršić, V. Litovski, M. Jakovljević, H. Detter 475

SPICE Electrothermal Modeling of Power Integrated Circuits

A. Maxim, D. Andreu, J. Boucher 479

Poster Session Process and Device Simulation

Numerical Simulation of Plasma-Chemical Etching Reactors

Y. Grigoryev, A. Gorobchuk 485

Simulation of Electron Heating in n-Channel Submicron Si-MOSFET's

V. Borzdov, V. Galenchik, F. Komarov, S. Mulyarchik, O. Zhevnyak 489

Dynamical Model for GaAs Optical FETS in 0-120°C Temperature Range

R. Ramović, R. Andrin, D. Grbović 493

Microplasma and Uniform MESFET Gate Breakdown

V. Vashchenko, J. Martyanov, V. Sinkevitch 497

Modeling Optical Response of the GaAs MESFET using PSPICE Circuit Simulator

V. Ivanović 501

Two-Dimensional Modeling of On State Voltage Drop in IGBT

E. Napoli, P. Spirito, A. Strollo 505

An Advanced PNP Bipolar Transistor Design for Low-Power and Very-High-Performance Quarter-Micron CBiCMOS Process

B. Djezzar, M. Belaroussi 509

Session Microsystem Technologies and Devices

An Integrated Microstructure with Temperature Control for Gas Sensors G. Cardinali, L. Dori, M. Fiorini, P. Maccagnani, V. Liberali	515
Micromachined Milimeter-Wave Technology A. Saint-Etienne, B. Guillon, P. Pons, G. Blasquez, T. Parra, P. Blondy, J. C. Lalaurie, R. Plana, F. J. Graffeuil	519
High Frequency Circuits Manufactured by Micromachining Techniques B. Milovanović, V. Marković, D. Stojković	523
Piezoresistive Force Sensor Developed for Use in Handling of Microparts N. Delić, A. Vujanić, H. Detter, Z. Djurić, N. Simičić, R. Petrović	527
Micromachined Silicon Sensor for Tribological Investigations A. Vujanić, N. Delić, A. Pauschitz, H. Detter, N. Simičić, M. Matić	531
The Measurement of Minimotors and Micromotors Torque Characteristic W. Brenner, G. Haddad, G. Popović, A. Vujanić, G. Abraham, A. Matzner	535
Spark Erosion for Fabrication of Micromechanical Components - Evaluation of Possibilities and Limits P. Herbst, G. Popović, H. Detter, W. Brenner, D. Petrović, N. Delić, A. Vujanić	539
Thin-Film Microprobe with Bilayer Lipid Membrane for Advanced pH-meter V. Tvarožek, A. Ottova-Leitmannova, I. Novotny, V. Rehacek, F. Mika, H. Ti Tien	543
SnO₂ Based Sensors of Smoke V. Brynzari, S. Dmitriev, G. Korotchenkov	547
Ge Films on GaAs: Preparation, Properties and Application to Temperature Sensors V. Mitin	551

Poster Session Microsystem Technologies and Devices

Compensation of Thermocouple Reference Junction Temperature Variation by a Silicon Temperature Sensor M. Zlatanović, M. Djukić, I. Popović, Z. Zirojević	557
Fiber-Optic Displacement Sensor S. Živanović, J. Elazar, M. Tomić	561
Dynamic and Static Characteristics Investigation of Integrated Radiation Thermopile Sensor R. Tmušić, A. Djurišić, D. Stanković	565
Transient Analysis of Compensated Hall-Effect Current Transducers P. Pejović, D. Stanković	569
Faraday Cell Optimization J. Bandić, G. Mašanović, J. Radunović	573
Space Communication with a Descending Apparatus on the Base of Microwave Antenna S. Koshevaya, N. Kotsarenko, E. Gutierrez-D, L. Bedareva	577

Session Device Reliability and Characterization

Invited Keynote Paper

Basics and Applications of Charge Pumping in Submicron MOSFETs

G. Groeseneken, H. Maes 581

Invited Keynote Paper

Current Status of Failure Analysis for ULSIs

S. Nakajima, T. Ueki, Y. Shionoya, K. Mafune, N. Kuji, S. Nakamura, Y. Komine, T. Takeda 591

Geometric Current Component in Charge Pumping Measurements

P. Habaš, G. Groeseneken, G. Van Den Bosch 599

Analytical Model and Qualitative Analysis the Interface-Trap Charge-Pumping Characteristics of MOS Structure

P. Habaš 605

Electrical Characteristics of NO Nitrided SiO₂ Grown on p-type 4H-SiO₂

H. Li, S. Dimitrijević, H. Harrison, D. Sweatman, P. Tanner 611

Electrical Properties of Thin Ta₂O₅ Films Obtained by Thermal Oxidation of Ta on Si

E. Atanassova, D. Spassov 613

RIE Nitrogen Plasma-Induced Structural Changes in Thin SiO₂ Layers

E. Atanassova, A. Paskaleva 617

Gate Oxide Degradation Due to Trapping of Positive Charges During Fowler-Nordheim Stress at Low Electron Fluence: A Rigorous Model

P. Samanta, C. Sarkar 621

Simulation of Hot Carrier Reliability in MOS Integrated Circuits

H. Wong, M. C. Poon 625

2D Modeling of Mechanical Stress Evolution and Electromigration in Confined Aluminum Interconnects

V. Petrescu, T. Mouthaan 629

Persistent Photoconductivity as a Tool for Monitoring Oxide Clusters Concentration in Silicon Wafers

Y. Haddab, D. Manić, R. Popović 633

Influence of Assembling Procedure on IC Parameters

D. Manić, A. Friedrich, Y. Haddab, R. Popović 637

Qualifying ICs for Space Environments with the Help of Parameters Modeling

I. Shvetzov-Shilovsky, V. Belyakov, S. Cherepko, V. Pershenkov, V. Emelyanov 641

Investigation of Silicon Device Processes Using Scanning Probe Microscopy

M. Radhakrishnan, Y. Lee, D. Poenar, T. Chai, M. Natarajan 645

Poster Session Device Reliability and Characterization

A Biased Percolation Model for the Analysis of Electronic Device Degradation

Z. Gingl, C. Pennetta, L. B. Kiss, L. Reggiani 651

Modeling of Gate Dielectric Breakdown Due to Drain Avalanche Injection in MOSFETs

H. Wong, M. C. Poon 655

Correspondence Between Gated-Diode Drain Current and Charge Pumping Current in Hot-Carrier Stressed n- and p-MOSFETs	
Y. H. Goh, C. H. Ling	659
Thin Film Resistor Technology and Noise Reliability Indicators	
P. Hruska	663
Reliability Testing of Power VDMOS Transistors	
N. Tošić, B. Pešić, N. Stojadinović	667

Session Circuit Design and Application

Invited Keynote Paper

Design of High Speed Analog Circuits for Mobile Communications	
F. Maloberti	673

Invited Keynote Paper

A New Opportunity by Low Power CMOS Decision Circuit for Optical Communications and Its Comparison with New GaAs and HBT Implementation	
M. Lee	681

CMOS Bridge to Frequency Converter with Gain and Offset Control	
D. McDonagh, K. Arshak	689

Low-Power High Bandwidth CMOS Current Conveyor	
J. Popović, A. Pavasović, D. Vasiljević	693

High Performance Analog Behavioral Modeling of Operational Amplifiers	
A. Maxim, D. Andreu, A. Gaci, J. Boucher	697

A Fast and Area Efficient Complementary Pass-Transistor Logic Carry Skip Adder	
A. Strollo, E. Napoli	701

Symbolic Approximation of Circuit Response Containing Negative Terms	
I. Markoski, D. Tošić	705

Symbolic Approach to 2-D Biorthogonal Diamond-Shaped Filter Design	
D. Tošić, A. Mojsilović, M. Popović	709

Symbolic Analysis of Programmable Digital Filters	
M. Lutovac, D. Tošić, B. Evans	713

Automatic Symbolic Analysis of SC Networks Using Modified Nodal Approach	
V. Živković, P. Petković, D. Milovanović	717

Multi-Valued Simulation of Digital Circuits	
R. Ubar	721

Technical University of Tallinn, Estonia

VHDL - AleC++ Co-simulation	
Ž. Dimić, M. Damnjanović, V. Litovski	725

SIGGEN: A $\Sigma\Delta$ DAC Autogeneration Tool	
K. Rowley, C. Lyden	729

Transforming Integrated Circuit Layout Description from the Unrestricted to a Restricted Format	
D. Janković, D. Milenović, Z. Stamenković	733

A High Speed Serial Bus Controller ASIC	
N. Kero, S. Janković, W. Fallman, V. Litovski	737

Poster Session Circuit Design and Application

A Simple Technique to Increase the Switching Speed of the MOS Transistor	
G. Brezeanu, F. Mitu, G. Dilimot, I. Enache	743

CMOS Adaptive Biasing Circuits for Low Power Applications	
G.-C. Cardarilli, G. Ferri	747

Modeling of Chaotic Characteristics in Integrated Phase-Locked Loop	
W. Siu, H. Wong, T. Cheung, K. Man	751

CMOS Voltage-Controlled Oscillator Based on Current Conveyor	
J. Popović, A. Pavasović, D. Vasiljević	755

Submicron CMOS Transient Test Structure for Low Power VLSI	
M. Lee	759

Novel Floating-Impedance Converter Using CCII+	
C-L. Hou, R. Yean, W-Y. Wang	763

Simulation of Open and Shorted RC Interconnect Waveforms for Voltage Step Function with Low and High Transient Response	
K. El-Shennawy	767

Iddq Fault Model Generation for BiCMOS and CMOS Circuits	
V. Panić, D. Milovanović	771

3rd-order Chebyshev Lowpass Filter Using Phase-Compensated CMOS OTA	
Z. Stanimirović, I. Mrak, M. Hribšek	775

Testable Design of Digital ASIC with Embedded Analog Multiplexer	
S. Janković, D. Maksimović, P. Petković, V. Litovski	779

Symbolic Oriented Stuck Fault Modelling of CMOS Sequential Circuits	
P. Petković, D. Milovanović, V. Živković	783

A Combination of Wave-Pipelining Timing Methodology and DPTL Circuit Design Technique	
P. Marković, D. Simić	787

Effect of GaAs MESFET's Imperfections, Gamma-Radiation, and Temperature on the Performance of Microwave Active Filters	
A. El-Kabbani, I. El-Shahat, F. Soliman, F. Farag	791

10 GHz Double Barrier Tunneling Diode Microwave Integrated Circuit Oscillator Design	
D. Neculoiu, D. Dobrescu, T. Tebeanu	797

Session System Design and Testing

Invited Keynote Paper

Differential and Pass-Transistor CMOS Logic for High-Performance Systems V. Oklobdzija	803
Low Power, Process Independent, Full Transistor Controlled Slew Rate, PCI Compliant I/O Pads F. Wajsburt, K. Dioury, F. Petrot	811
Compact Parallel Multipliers Using the Sign-Generate Method in FPGA S. Tagzout, L. Sahli	815
Asynchronous Controller for Token-Ring Mutual Exclusion: Delay-Insensitive Arbiter Cell M. Tošić, M. Stojčev, G. Djordjević	819
Asynchronous Controller for Token-Ring Mutual Exclusion: Ring Design M. Tošić, M. Stojčev, G. Djordjević	823
Evaluating Two-Bit Branch Predictors for User/Kernel Code M. Petrović, I. Tartalja	827

Poster Session System Design and Testing

A Quantitative Analysis of Wiring Lengths in 2D and 3D VLSI Implementations of 2D Systolic Arrays A. Milenković, V. Milutinović	833
Reflective Memory System Based on a Grid of Buses that Selectively Uses Relaxed Memory Consistency Models J. Protić, V. Milutinović	837
Limes: A Multiprocessor Simulation Environment for PC Platforms D. Magdić	841
Interconnection Networks for Sea-of Gates VLSI: Comparative Analysis of Performance and Complexity D. Milutinović	845
An Approach to Design for Testability in Hard Real-Time Systems M. Jevtić, M. Damjanović	849